

## NplusT Unveils TMC-100: Advanced Reliability Evaluation Solution for Neuromorphic Computational Arrays

NplusT, a leading Italian supplier of storage test solutions, proudly announces the release of TMC-100, the latest configuration in its TESTMESH family. This cutting-edge solution is designed specifically for the reliability evaluation of neuromorphic computational arrays.



Building on the robust and versatile TESTMESH architecture, the TMC-100 introduces a suite of advanced features tailored for the unique demands of neuromorphic computing:

- **Aging and Stress Testing:** The TMC-100 excels in performing extensive aging and stress tests, ensuring the long-term reliability of computational arrays.
- **High-Speed Cycling:** This feature enables rapid aging cycles, significantly accelerating the testing process and providing quicker insights into device performance over time.
- **Precision Multilevel and Analog Cell Management:** The TMC-100 offers unparalleled accuracy in managing multilevel and analog cells, crucial for the nuanced requirements of neuromorphic systems.

The TMC-100 is equipped with state-of-the-art analog instrumentation, including waveform generators, reference voltages, and current sensing and measurement circuits. Additionally, it incorporates digital signal capabilities to effectively characterize complex test arrays. A dedicated multiplexer routes tester signals to the rows and columns of the NVM array, ensuring precise and reliable evaluation.

NplusT's TMC-100 represents a significant advancement in the field of neuromorphic array testing, providing researchers and developers with a powerful tool to push the boundaries of computational technology.

For more information, please contact us at [info@n-plus-t.com](mailto:info@n-plus-t.com) or visit us at booth 749 during the Flash Memory Summit (FMS).